

## N-Channel Enhancement Mode MOSFET

### Features

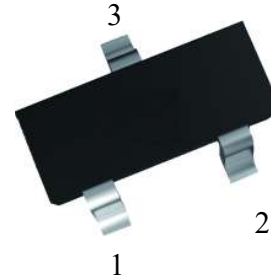
- Surface-mounted package
- Extremely low threshold voltage
- Advanced trench cell design
- ESD protected ( HBM > 2KV )

### Applications

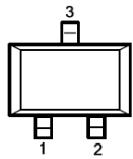
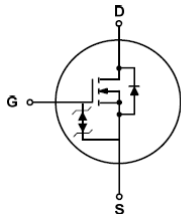
- Portable appliances

### Quick reference

- $BV \cong 60\text{ V}$     $P_{tot} \cong 0.83\text{ W}$     $ID \cong 0.43\text{ A}$
- $R_{DS(ON)} \cong 3\ \Omega @ V_{GS} = 10\text{ V}$
- $R_{DS(ON)} \cong 4\ \Omega @ V_{GS} = 4.5\text{ V}$



### Pin Description

Pin Description	Simplified Outline	Symbol
1 Gate(G)		
2 Source(S)		
3 Drain(D)		

### Limiting Values

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	Drain-Source Voltage	$T_A = 25\text{ }^\circ\text{C}$	-	60	V
$V_{GS}$	Gate-Source Voltage	$T_A = 25\text{ }^\circ\text{C}$	-	$\pm 20$	V
$I_D^*$	Drain Current	$T_A = 25\text{ }^\circ\text{C}, V_{GS} = 10\text{ V}$	-	0.43	A
$I_{DM}^{***}$	Pulsed Drain Current	$T_A = 25\text{ }^\circ\text{C}, V_{GS} = 10\text{ V}$	-	1.7	A
$P_{tot}^*$	Total Power Dissipation	$T_A = 25\text{ }^\circ\text{C}$	-	0.83	W
		$T_A = 100\text{ }^\circ\text{C}$	-	0.33	
$T_{stg}$	Storage Temperature		- 55	150	$^\circ\text{C}$
$T_J$	Junction Temperature		-	150	$^\circ\text{C}$
$I_S^*$	Diode Forward Current	$T_A = 25\text{ }^\circ\text{C}$	-	0.4	A
$R_{\theta JA}^*$	Thermal Resistance- Junction to Ambient		-	150	$^\circ\text{C} / \text{W}$

Notes : \* Surface Mounted on 1 in<sup>2</sup> pad area, t ≤ 10 sec      \*\* Pulse width ≤ 300 μs, duty cycle ≤ 2 %

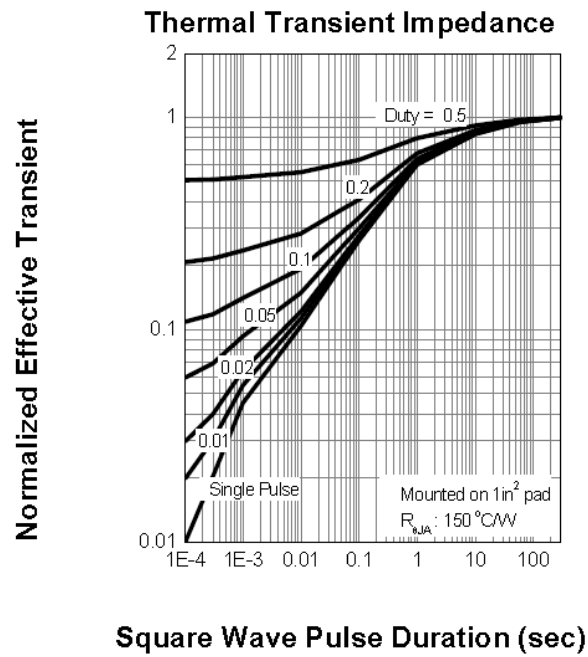
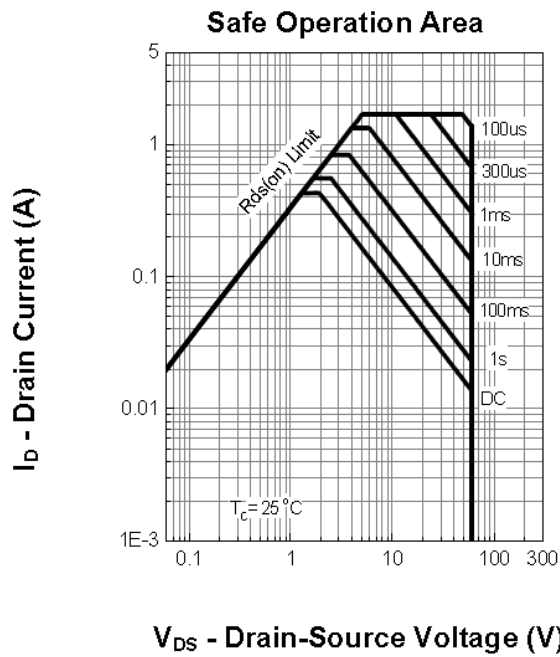
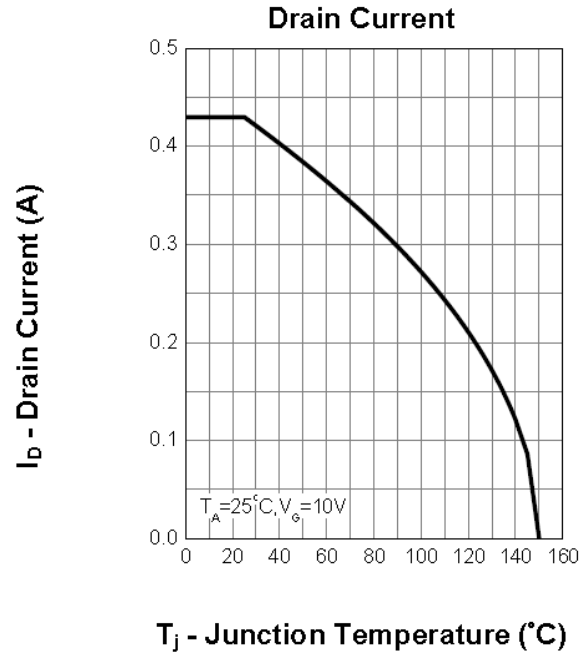
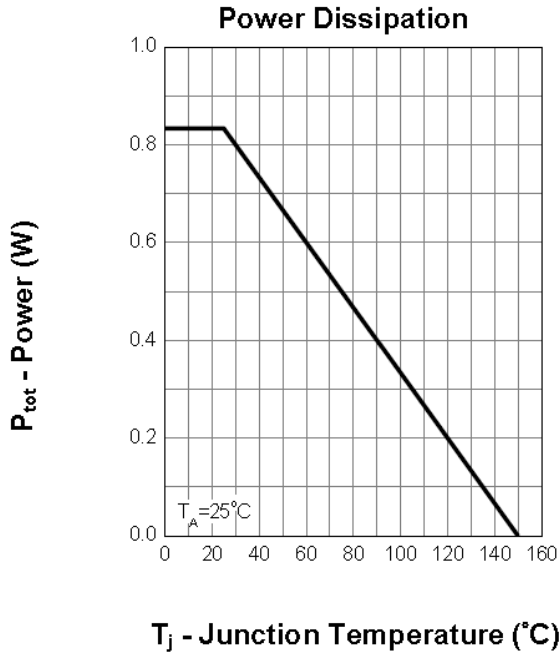
**Electrical Characteristics ( TA = 25 ° C Unless Otherwise Noted )**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_{DS} = 250\ \mu\text{A}$	60	-	-	V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = 250\ \mu\text{A}$	0.9	1.6	2.5	V
$I_{DSS}$	Drain Leakage Current	$V_{DS} = 48\text{ V}, V_{GS} = 0\text{ V}$	-	-	1	$\mu\text{A}$
		$T_J = 85\text{ }^\circ\text{C}$	-	-	30	$\mu\text{A}$
$I_{GSS}$	Gate Leakage Current	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$	-	-	$\pm 10$	$\mu\text{A}$
$R_{DS(ON)}^a$	On-State Resistance	$V_{GS} = 10\text{ V}, I_{DS} = 0.4\text{ A}$	-	1.9	3.0	$\Omega$
		$V_{GS} = 4.5\text{ V}, I_{DS} = 0.3\text{ A}$	-	2.4	4.0	
<b>Diode Characteristics</b>						
$V_{SD}^a$	Diode Forward Voltage	$I_{SD} = 0.4\text{ A}, V_{GS} = 0\text{ V}$	-	0.7	1.3	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 0.4\text{ A}, dI_{SD}/dt = 100\text{ A}/\mu\text{s}$	-	40	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	40	-	nC
<b>Dynamic Characteristics<sup>b</sup></b>						
$R_G$	Gate Resistance	$V_{GS} = V_{DS} = 0\text{ V}, F = 1\text{ MHz}$	-	130	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}$ Frequency = 1 MHz	-	30	-	pF
$C_{oss}$	Output Capacitance		-	4.2	-	
$C_{rss}$	Reverse Transfer Capacitance		-	3	-	
$t_{d(on)}$	Turn-on Delay Time	$V_{DS} = 30\text{ V}, V_{GEN} = 10\text{ V},$ $R_G = 25\ \Omega, R_L = 150\ \Omega,$ $I_{DS} = 0.2\text{ A}$	-	3.9	9	ns
$t_r$	Turn-on Rise Time		-	3.5	8	
$t_{d(off)}$	Turn-off Delay Time		-	16	40	
$t_f$	Turn-off Fall Time		-	10	20	
$Q_g$	Total Gate Charge	$V_{GS} = 4.5\text{ V}, V_{DS} = 10\text{ V},$ $I_{DS} = 0.4\text{ A}$	-	305	-	pC
$Q_{gs}$	Gate-Source Charge		-	85	-	
$Q_{gd}$	Gate-Drain Charge		-	205	-	

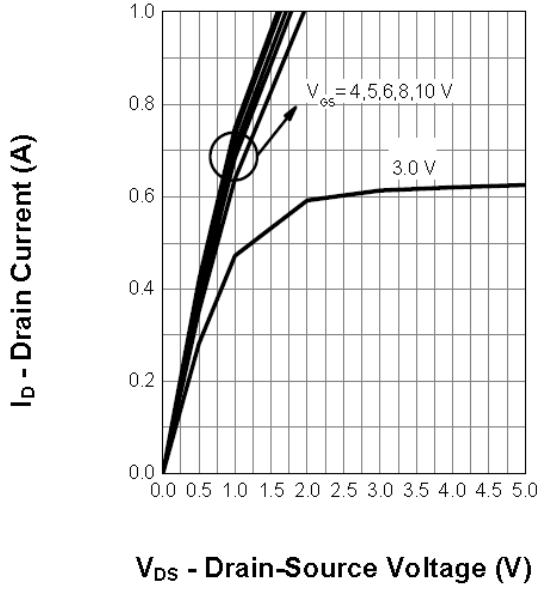
Notes : a : Pulse test ; pulse width  $\leq 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$

b : Guaranteed by design, not subject to production testing

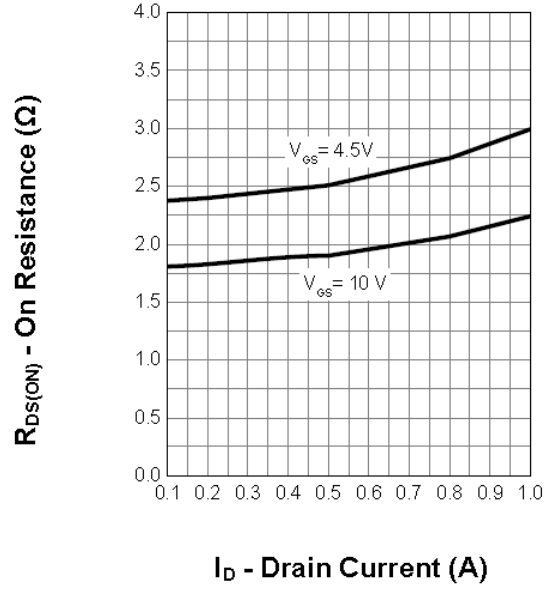
## Typical Characteristics



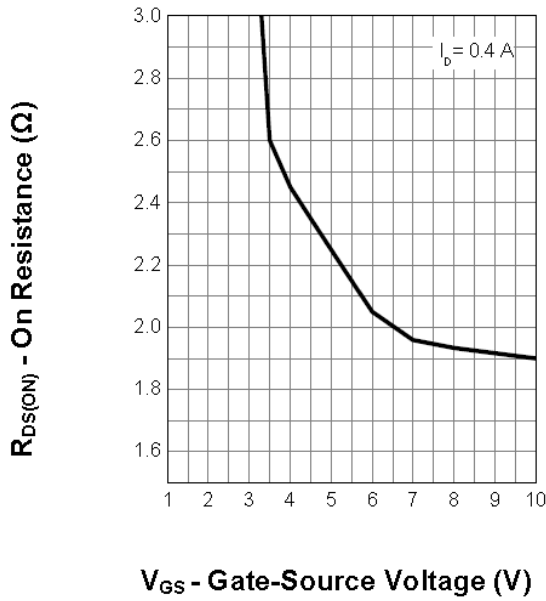
**Output Characteristics**



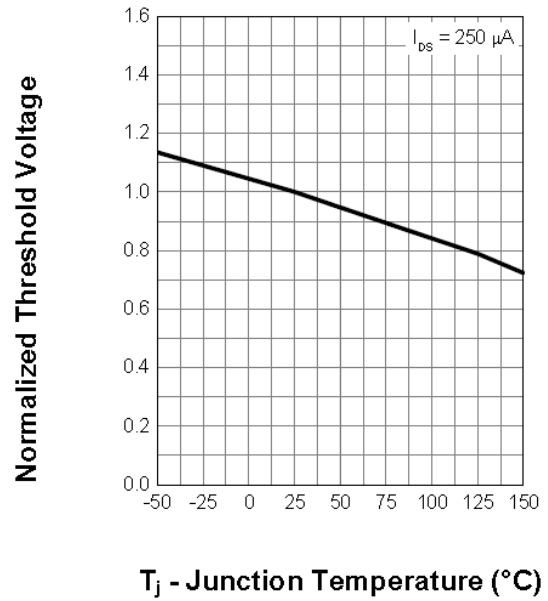
**Drain-Source On Resistance**

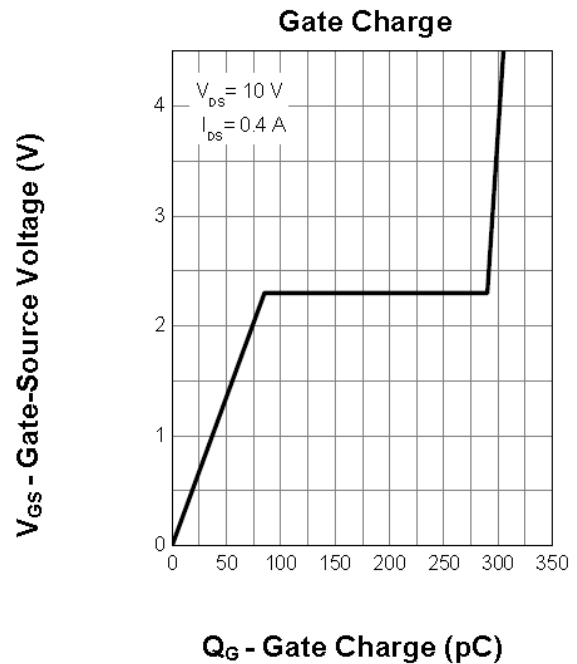
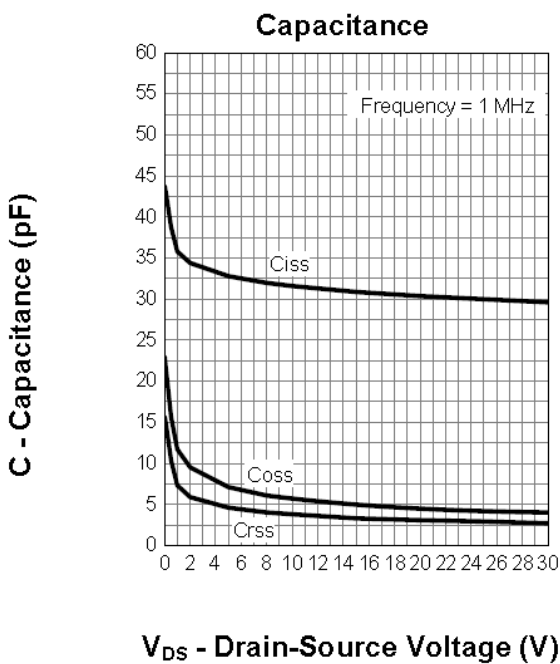
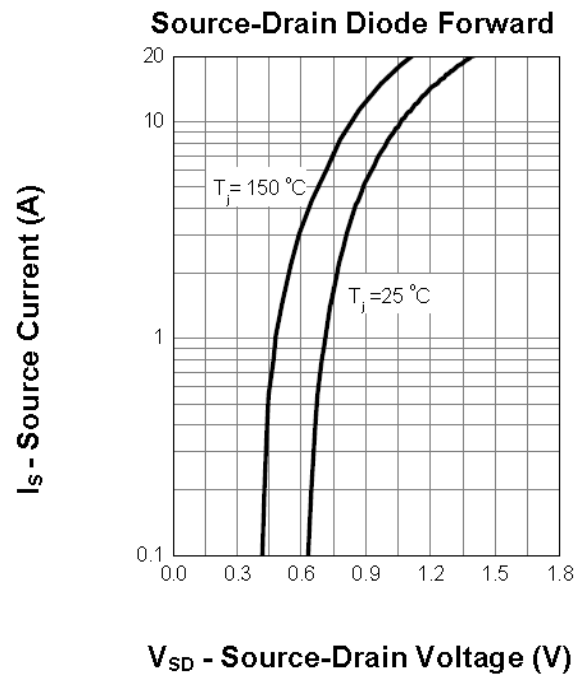
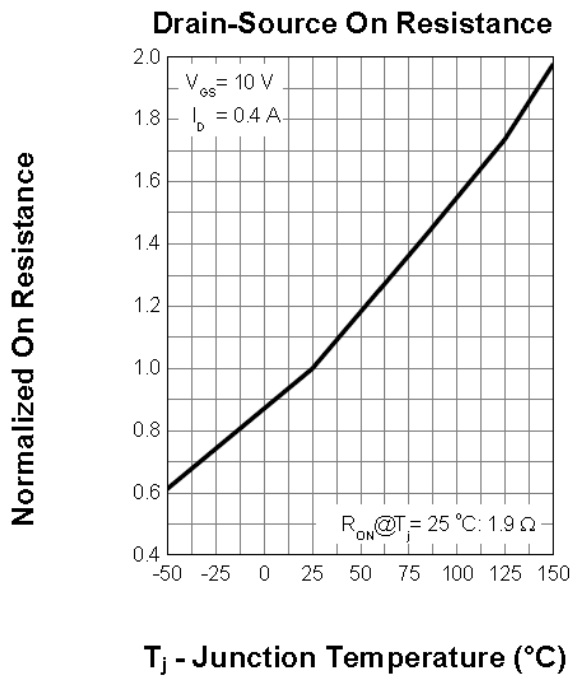


**Transfer Characteristics**

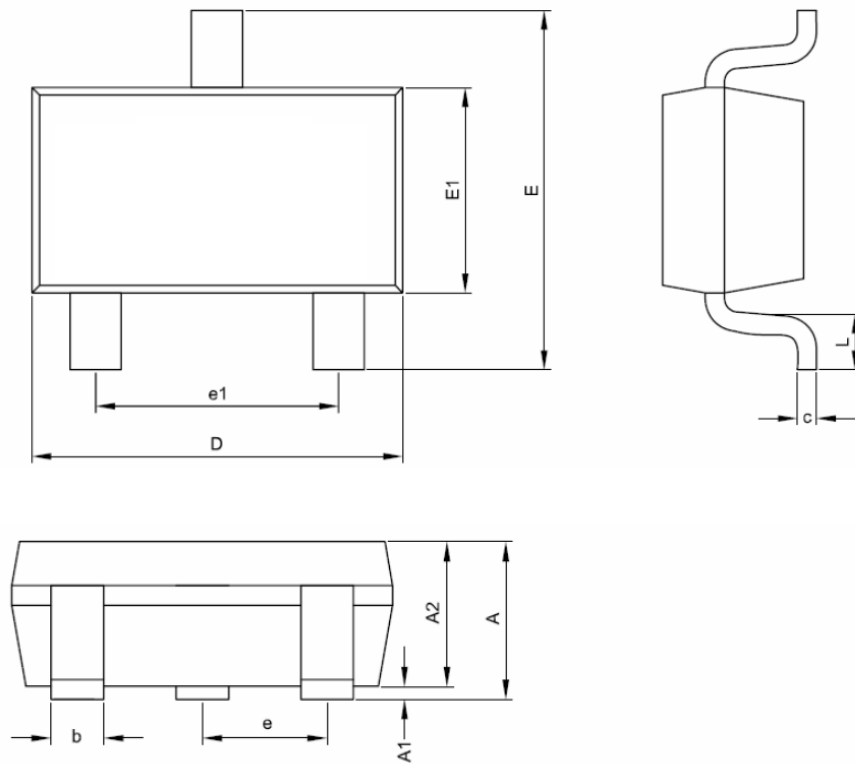


**Gate Threshold Voltage**





Package Dimensions  
SOT-23



Symbol	Dimensions In Millimeters	
	MIN.	MAX.
A	—	1.12
A1	0.00	0.1
A2	0.90	1.02
D	2.90 BSC	
E	2.40 BSC	
E1	1.20	1.40
c	0.08	0.25
b	0.30	0.50
e	0.95 BSC	
e1	1.90 BSC	
L	0.20	0.60